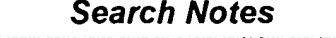


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/669,854	IKEDA, IKUYO
	Examiner	Art Unit
	Quoc A. Tran	2176

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
715	527	6/24/2006	
715	863	6/24/2006	
358	1.15	6/24/2006	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	7/9/2005	<i>[Signature]</i>
EAST (US-PAT, US-PGPUB) see Search Histoty Printout	7/9/2005	<i>[Signature]</i>
NPL IEEE DataBase see Search History Printout	7/9/2005	<i>[Signature]</i>
Updated Above	11/25/2005	<i>[Signature]</i>
EAST (UAPAT, USPGPUB, EPO JPO, DERWENT, USOCR, IBM_TDB) See Search History Printout	6/24/2006	<i>[Signature]</i>
ACM Digital library& STIC Search (see search Prinout)	6/24/2006	<i>[Signature]</i>
Interference Search (EAST US-PGPUB) see search printout	6/24/2006	<i>[Signature]</i>
Consulting Primary Examiner Jerome Grant II TC - 2625	6/22/2006	<i>[Signature]</i>

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SEARCHED

Class	Sub.	Date	Exmr.
715	530	1/21/03	BT
707	1 10 102 104.1		
709	201 217		
345	469 764 422 801		
358	1.14 449 474 296		
715	512 517 541	↓	↓
358	1.15	BT 3/5/04	BT
	↓	↓	↓

INTERFERENCE SEARCHED

Class	Sub.	Date	Exmr.

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

See ATTACHMENT For SEARCH HISTORY	Date	Exmr.
"PLUS"	1/21/03	BT
"EAST"	1/24/03	BT
up date above	3/5/04	BT

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Search Notes	Application No.	Applicant(s)
	09/669,854	IKEDA, IKUYO
	Examiner	Art Unit
	Quoc A. Tran	2176